

# APPROVAL SHEET

## MULTILAYER CERAMIC CAPACITORS

Low Profile Series

0402 to 1210 Sizes

X7R, X5R & Y5V Dielectrics

Halogen Free & RoHS Compliance



\*Contents in this sheet are subject to change without prior notice.

## 1. DESCRIPTION

MLCC consists of a conducting material and electrodes. To manufacture a chip-type SMT and achieve miniaturization, high density and high efficiency, ceramic condensers are used.

WTC TT series MLCC is used in product having thickness concerned generally have high capacitance and thinner product thickness. The high dielectric constant material X7R, X5R and Y5V are used for this series product.

## 2. FEATURES

- a. Standard size with thin thickness.
- b. Small size with high capacitance.
- c. Capacitor with lead-free termination (pure Tin).

#### 3. APPLICATIONS

- a. For LCD panels.
- b. For PCMCA cards.
- c. For IC packaging and modules.
- d. Any thickness concerned products.

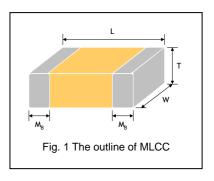
### 4. HOW TO ORDER

<u>TT</u>	<u>15</u>	<u>X</u>	<u>475</u>	<u>M</u>	<u>6R3</u>	<u>C</u>	Ī
<u>Series</u>	Size	Dielectric	<u>Capacitance</u>	Tolerance	Rated voltage	<u>Termination</u>	<u>Packaging</u>
	45 0400 (4005)	<b>D</b> V7D	Z NE LE K	1/4 × 1		<b>2</b> 0 (NI)(0	
TT=Low profile	<b>15</b> =0402 (1005)		Two significant	<b>K</b> =±10%	Two significant	<b>C</b> =Cu/Ni/Sn	T=7" reeled
	<b>18</b> =0603 (1608)	<b>X</b> =X5R/4//	digits followed by	M=±20%	digits followed by		G=13" reeled
	<b>21</b> =0805 (2012)	F=Y5V 777/4	no. of zeros. And	<b>Z</b> =-20/+80%	no. of zeros. And		
	<b>31</b> =1206 (3216)		R is in place of		R is in place of		
	<b>32</b> =1210 (3225)		decimal point.	54	decimal point.		
		9	PASSIVE SYS	TEM ALLIANCE	cpa calloc		
		1월	eg.:		<b>6R3</b> =6.3 VDC		
		图	475=47x10 <sup>5</sup>		<b>100</b> =10 VDC		
		1	=4,700,000pF		<b>160</b> =16 VDC		
		E	=4.7µF	100	<b>250</b> =25 VDC		
			Alco Chro	CO/	<b>500</b> =50 VDC		
			JEON JEON	UBY	<b>101</b> =100 VDC		



## **5. EXTERNAL DIMENSIONS**

Size Inch (mm)	L (mm)	W (mm)	T (mm)/Sy	mbol	M <sub>B</sub> (mm)
0402 (1005)	1.00±0.2	0.5±0.2	0.30±0.03	L	0.25±0.10
0603 (1608)	1.6+0.15/-0.10	0.8+0.15/-0.10	0.50±0.10	Н	0.40±0.15
0805 (2012)	2.00±0.20	1.25±0.20	0.85±0.10	Т	0.50±0.20
1206 (2216)	2 20 . 0 20	1.60.0.20	0.85±0.10	Т	0.60.0.20
1206 (3216)	3.20±0.20	1.60±0.20	1.15±0.15	J	0.60±0.20
1210 (2225)	2 20 . 0 20	2.50.0.20	0.85±0.10	Т	0.75 . 0.25
1210 (3225)	3.20±0.30	2.50±0.20	2.00±0.20	K	0.75±0.25



## **6. GENERAL ELECTRICAL DATA**

Dielectric	X7R	X5R	Y5V				
Size		0402, 0603, 0805, 1206, 1210					
Capacitance range*	1μF to 10μF	0.22μF to 22μF	1μF to 10μF				
Capacitance tolerance**	K (±10%)	K (±10%), M (±20%)					
Rated voltage (WVDC)	10V, 16V, 25V, 50V, 100V	6.3V, 10V, 16V, 25V	10V, 16V, 25V, 50V				
Operating temperature	-55 to +125℃	-55 to +85℃	-25 to +85℃				
Capacitance characteristic	±15% +30/-80%						
Termination	Ni/Sn (lead-free termination)						

<sup>\*</sup> Measured at 1.0±0.2Vrms, 1.0kHz±10%, 30~70% related humidity, 25°C ambient temperature for X7R, X5R and at 20°C for Y5V.

<sup>\*</sup> Reflow soldering process only is recommended.

<sup>\*\*</sup> Preconditioning for Class II MLCC: Perform a heat treatment at 150±10°C for 1 hour, then leave in a mbient condition for 24±2 hours before measurement.

**Multilayer Ceramic Capacitors** 

## 7. CAPACITANCE RANGE

#### 7-1 X7R dielectric

	Dielectric						X7R					
	Size		0805 1206			206 1210						
Rate	ed voltage (VDC)	10	16	25	50	10	16	25	50	10	16	100
	1.0µF (105)							Т				
a)	1.5µF (155)											
Capacitance	2.2µF (225)		Т	Т					Т			K
ita	3.3µF (335)											
ac	4.7μF (475)	Т						Т				
Sag	6.8µF (685)											
	10μF (106)					Т						
	22μF (226)											

#### 7-2 X5R dielectric

	Dielectric									K5R								
	Size		0402		06	03		30	305				1206			1210		
Rate	ed voltage (VDC)	6.3	10	25	10	16	6.3	10	16	25	6.3	10	16	25	50	10	16	25
	0.22uF (224)			L	Н	Н												
	0.47uF (474)	L		L														
	1.0µF (105)	L			Н	Н		Т	Т	Т		Т	Т	Т				
e	1.5µF (155)							T	Т			Т	Т	Т				
au	2.2µF (225)	L					7 -	HT	T	J		Т	Т	Т	Т			
<u>ci</u>	3.3µF (335)					126	775	3_	7	7		Т	Т	Т		Т		
Capacitance	4.7µF (475)	L			Н	NO.	T	πT	7 T	1		Т	Т	Т		Т		
ပိ	6.8µF (685)				AY		场	报[7]	万荟	- 75	2							
	10µF (106)				140	1	XT.	Т	T	150	<b>(</b> 0,0	J/T		Т		Т		Т
	22uF (226)				177177	<b>*</b>	Т	Т		<f' -<="" th=""><th></th><th>31</th><th>Т</th><th></th><th></th><th></th><th>Т</th><th></th></f'>		31	Т				Т	
	47uF (476)				17						T							

#### 7-3 Y5V dielectric

	Dielectric				DACETVE !	EVETEN ALI	Y5V				
	Size		0	305				206		12	10
Rate	ed voltage (VDC)	10	16	25	50	10	16	25	50	10	16
	1.0µF (105)		1	0	) T		(O)	\$2/			
	1.5µF (155)			4/11	19ch		0110	3			
ဗ	2.2µF (225)		Т	35/1		OIOEA,	T	T	Т		
<u> </u>	3.3µF (335)	Т			(ECHNOLO	OL CORROLL	TIMI.				
ac	4.7μF (475)	Т	Т		J. I.A.O.T.O.	JY EUKYUN	T				
Capacitance	6.8µF (685)					T					
	10μF (106)	Т				Т				Т	
	22μF (226)										

## **8. PACKAGING STYLE AND QUANTITY**

Size	Thickness May (mm)	VC vm b a l	7" reel				
Size	ze Thickness Max (mm)/Symbol		Paper tape	Plastic tape			
0402 (1005)	0.33	L	15k	-			
0603 (1608)	0.60	Н	4k	-			
0805 (2012)	0.95	Т	4k	-			
4000 (0040)	0.95	Т	4k	-			
1206 (3216)	1.30	J	-	3k			
1210 (2225)	0.95	Т	-	3k			
1210 (3225)	2.00	К	-	1k			

Unit: pieces



**Approval Sheet** 

## 9. RELIABILITY TEST CONDITIONS AND REQUIREMENTS

No.	Item	Test Condition	Requirements				
1.	Visual and		* No remarkable defect.				
	Mechanical		* Dimensions to conform to individual specification sheet.				
2.	Capacitance	Cap≤10µF, 1.0±0.2Vrms, 1kHz±10% Cap>10µF, 0.5±0.2Vrms, 120Hz±20%**	* Shall not exceed the limits given in the detailed spec.				
3.	Q/ D.F.	** Test condition: 0.5±0.2Vrms , 1KHz±10%	X7R/X5R: Rated vol. D.F.				
	(Dissipation	TT18X≧475(10V) , TT15X series	100V ≤5%				
	Factor)	*Before initial measurement (Class II only): To apply de-aging	50V, 25V, 16V, 10V ≤10% 6.3V ≤15%				
		at 150°C for 1hr then set for 24±2 hrs at room temp.	Y5V:				
			Rated vol. D.F.				
			50V   ≤7%     25V   ≤9%				
			16V/10V ≤12.5%				
4.	Dielectric	* To apply voltage: 250% rated voltage.	* No evidence of damage or flash over during test.				
	Strength	* Duration: 1 to 5 sec. * Charge and discharge current less than 50mA.					
5.	Insulation	* To apply rated voltage for max. 120 sec.	≥10GΩ or RxC≥100Ω-F whichever is smaller.				
	Resistance						
6.	Temperature	With no electrical load.					
	Coefficient	T.C. Operating Temp  X7R -55~125℃ at 25℃	T.C. Capacitance Change				
		X5R -55~85℃ at 25℃	X7R Within ±15%				
		Y5V -25~85°C at 20°C *Before initial measurement (Class II only);	X5R Within ±15%				
		To apply de-aging at 150℃ for 1hr then set for 24± 2 hrs at	Y5V Within +30%/-80%				
		room temp.					
		01005 0201 Cap≤0.01µF: 0.5V Cap<0.1µF:1V					
		Cap>0.01µF: 0.2V	(F=\ \frac{1}{2}\)				
		*0201X104/16V: 0.5V	$\nabla C$				
		0402 0603 Cap<1µF: 1V Cap≤1µF: 1V					
		Cap=1μF: 0.5V       1μF <cap≤4.7μf: 0.5v<="" th="">         1μF<cap<10μf: 0.2v<="" td="">       Cap&gt;4.7μF: 0.2V</cap<10μf:></cap≤4.7μf:>					
		Cap≥10µF: 0.1V PASSIVE SYSTEM ALI 0805 1206/1210	TANCE S S				
		Cap<10μF: 1V					
		Cap>10μF: 0.2V Cap>10μF: 0.2V	75 SS				
7.	Adhesive	* Pressurizing force : 5N (≤0603) and 10N (>0603)	* No remarkable damage or removal of the terminations.				
	Strength of	* Test time: 10±1 sec.	No remarkable damage of removal of the terminations.				
	Termination	Fruncia	TON, Alle				
8.	Vibration	* Vibration frequency: 10~55 Hz/min.	* No remarkable damage.				
0.	Resistance	* Total amplitude: 1.5mm	* Cap change and Q/D.F.: To meet initial spec.				
	Resistance	* Test time: 6 hrs. (Two hrs each in three mutually perpendicular directions.)	oup thange and w.b.r To meet mind speed.				
		* Before initial measurement (Class II only):					
		To apply de-aging at 150℃ for 1hr then set for 24± 2 hrs at					
		room temp.  * Cap./DF(Q) Measurement to be made after de-aging at					
		150℃ for 1hr then set for 24±2 hrs at room temp.					
9.	Solderability	* Solder temperature: 235±5°C  * Dipping time: 2±0.5 sec.	95% min. coverage of all metalized area.				
10	Bending Test	* The middle part of substrate shall be pressurized by means	* No remarkable damage.				
. 3.		of the pressurizing rod at a rate of about 1 mm per second until	* Cap change :				
		the deflection becomes 1 mm and then the pressure shall be maintained for 5±1 sec.	X7R/X5R: within ±12.5%				
		* Before initial measurement (Class II only):	Y5V: within ±30%				
		To apply de-aging at 150℃ for 1hr then set for 24± 2 hrs at	(This capacitance change means the change of capacitance under				
		room temp.  * Measurement to be made after keeping at room temp. for	specified flexure of substrate from the capacitance measured before				
		24±2 hrs.	the test.)				
11.	Resistance to	* Solder temperature: 260±5℃ * Dipping time: 10+1 sec	* No remarkable damage.				
	Soldering Heat	* Dipping time: 10±1 sec * Preheating: 120 to 150℃ for 1 minute before imme rse the	* Cap change:				
		capacitor in a eutectic solder.	X7R/X5R: within ±7.5%				
		*Before initial measurement (Class II only): To apply de-aging at 150°C for 1hr then set for 24±2 hrs at room temp.	Y5V: within ±20%				
		*Cap. / DF(Q) / I.R. Measurement to be made after de-aging at	* Q/D.F., I.R. and dielectric strength: To meet initial requirements.				
		150℃ for 1hr then set for 24±2 hrs at room temp.	* 25% max. leaching on each edge.				

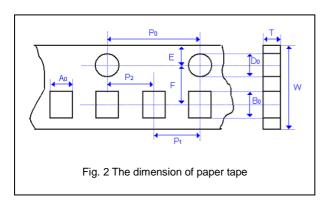
## **Multilayer Ceramic Capacitors**

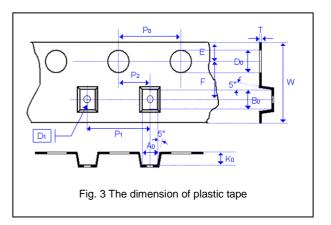


No.	Item		Test	Conditio	n			Requireme	ents
12.	Temperature	* Conduc	t the five cycles a	ccording to t	he temperatures and	,	No remarkable da	amage.	
	Cycle	time.				i	Cap change :		
		Step	Temp	o. (°C)	Time (min.)		X7R/X5R: within	±7.5%	
		1	Min. operating te	mp. +0/-3	30±3		Y5V: within ±20%	6	
		2	Room temp.		2~3				o meet initial requirements.
		3	Max. operating to	emp. +3/-0	30±3		Q/D.i., i.iv. and v	dielectric strength. To	o meet initial requirements.
		4	Room temp.	<u>'</u>	2~3				
		* Before i		nt (Class II o	nly): To apply de-agir	na			
		8	or 1hr then set fo		,, ,,,	.9			
		* Cap. / D	F(Q) / I.R. Measu	rement to be	e made after de-aging	g			
		at 150℃ f	or 1hr then set for	r 24±2 hrs at	room temp.				
13	Humidity	•	ıp.: 40±2℃		'	T	*No remarkable da		
.0.	-	1	•					7R/X5R: within ±25%	
	(Damp Heat)	1	y: 90~95% RH			ı	۲: *Q/D.F. value:	5V: within ±30%; 6.3	v, within +30/-40%
	Steady State		e: 500+24/-0hrs.	-+ (Ol II -	-1. A. T1 di.		X7R/X5R:		
		•			nly): To apply de-agir	ng	Rated vol.	D.F.	
		•	or 1hr then set for		·	_	100V	≤7.5%	
		1 '	` '		e made after de-agin	g	25V, 16V	≤15%	
		at 150℃ f	or 1hr then set for	r 24±2 hrs at	room temp.	ı	10V	≤20%	
						I	50V, 6.3V	≤30%	
					1 -		Y5V:	1-0070	
					公有	1	Rated vol.	D.F.	
				136	PIL	/_	50V	≤10%	
				V. RE	七阳仏		25V	≤15%	
			,	The same	YXIXIV	ス	16V, 10V	≤20%	
			/3	War La	KV				
4.4		<u> </u>					*No remarkable da	≥ 10 Ω-F whichever is	Smaller.
14.	Humidity		ip.: 40±2℃	444			*Cap change: X7	R/X5R: within ±25%	
	(Damp Heat)	* Humidity	y: 90~95%RH			Λ	Y:	5V: within ±30%; 6.3	V, within +30/-40%
	Load	* Test time	e: 500+24/-0 hrs.				*Q/D.F. value:		
		* To apply	voltage : Rated	voltage.	ASSIVE SYSTEM A	ALL	X7R/X5R:	2	
		* Before i	nitial measuremer	nt (Class II o	nly): To apply de-agir	ng	Rated vol.	D.F.	
		at 150℃ f	or 1hr then set for	r 24±2 hrs at	room temp.		100V	≤7.5%	
		* Cap. / D	F(Q) / I.R. Measu	rement to be	e made after de-agin	g	25V, 16V	≤15%	
		at 150℃	for 1hr then set for	or 24±2 hrs a	at room temp.		10V	≤20%	
				3/sa	ECHNOLOGY CORP	Ц	50V, 6.3V	≤30%	
				1911	FOUND		Y5V:		
					LYTHUI MAY MARPI	JB.	Rated vol.	D.F.	
					- 5001 COM.		50V	≤10%	
							25V	≤15%	
							16V, 10V	≤20%	
							*I.R.: 500MΩ or R	xC≧5 Ω-F whichever	r is smaller.
15	High	* Test tem	p. :			-	No remarkable da		
13.		-	R/X7E: 125±3℃			i		image. 'R/X5R: within ±25%	
	Temperature		V: 85±3℃			i		5V: within ±30%; 6.3	
	Load		e: 1000+24/-0 hrs		10		Q/D.F. value:		
	(Endurance)		voltage: 150% of rated voltage for	-	•	i	X7R/X5R:		
				Rated	Capacitance	i	Rated vol.	D.F.	
		Size	Dielectric	voltage	range	ĺ	100V	≤7.5%	
		TT15	X5R	6.3V	C≧1.0µF		25V, 16V	≤15%	
		TT18	Y5V	6.3V,10V	C≥2.2µF	ĺ	10V	≤20%	
		TT21	Y5V X5R/X7R/X6S	6.3V ≦10V	<u>C≧10μF</u> C≧10μF		50V, 6.3V	≤30%	
		TT31	Y5V	6.3V	C≧ 10µl C≧22µF	ĺ	Y5V:	•	_
						i	Rated vol.	D.F.	
				•	nly): To apply de-agin	g	50V	≤10%	
			or 1hr then set for		room temp . de-aging at 150℃ fo	١r	25V	≤15%	
			set for 24±2 hrs a			"	16V, 10V	≤20%	
						į		10 Ω-F whichever is:	 emaller
		:					\ 1312 UI KXU≦	10 12-1 WHIGHEVELIS	omalici.

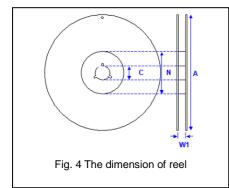
## **APPENDIXES**

## **■ Tape & reel dimensions**





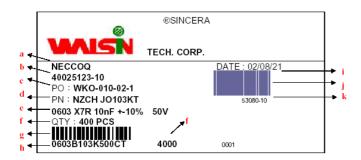
Size	0402	0603	0805	12	06	12	210
Thickness	L	Н	T	Т	J	Т	K
A <sub>0</sub>	0.70 +/-0.2	1.05 +/-0.30	1.50 +/-0.20	1.90 +/-0.50	< 2.00	< 3.05	1.05 +/-0.30
$B_0$	1.20 +/-0.2	1.80 +/-0.30	2.30 +/-0.20	3.50 +/-0.50	< 3.70	< 3.80	1.80 +/-0.30
Т	≦0.80	≦1.20	≦1.20	≦1.20	0.23 +/-0.1	0.23 +/-0.1	≦1.20
$K_0$	-	/- 'T #	¥ -	- V	< 2.50	< 1.50	-
w	8.00 +/-0.30						
P <sub>0</sub>	4.00 +/-0.10	4.00 +/-0.10	+/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10
10xP <sub>0</sub>	40.00 +/-0.20						
P <sub>1</sub>	2.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10
P <sub>2</sub>	2.00 +/-0.05	2.00 +/-0.05	2.00	2.00 +/-0.05	2.00 +/-0.05	2.00 +/-0.05	2.00 +/-0.05
D <sub>0</sub>	1.50 +0.1/-0	1.50 +0.1/-0	+0.1/-0	1.50 +0.1/-0	1.50 +0.1/-0	1.50 +0.1/-0	1.50 +0.1/-0
D <sub>1</sub>	-	-	-	-	1.00 +/-0.10	1.00 +/-0.10	-
E	1.75 +/-0.10						
F	3.50 +/-0.05						



Size	0402, 0603, 0805, 1206, 1210							
Reel size	7"	10"	13"					
С	13.0+0.5/-0.2	13.0+0.5/-0.2	13.0+0.5/-0.2					
$\mathbf{W}_1$	8.4+1.5/-0	8.4+1.5/-0	8.4+1.5/-0					
Α	178.0±1.0	250.0±1.0	330.0±1.0					
N	60.0+1.0/-0	100.0±1.0	100±1.0					



#### Example of customer label

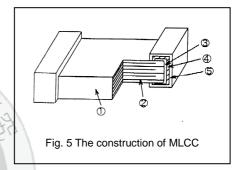


<sup>\*</sup>Customized label is available upon request

- a. Customer name
- b. WTC order series and item number
- c. Customer P/O
- d. Customer P/N
- e. Description of product
- f. Quantity
- g. Bar code including quantity & WTC P/N or customer
- h. WTC P/N
- i. Shipping date
- j. Order bar code including series and item numbers
- k. Serial number of label

#### Constructions

No.	Nam	ne	X7R, X5R, Y5V
①	Ceramic r	naterial	BaTiO₃ based
2	Inner ele	ctrode	斯阿恩
3		Inner layer	传吸份会
4	Termination	Middle layer	Ni Ni
(5)		Outer layer	Sn (Matt)



#### Storage and handling conditions

- (1) To store products at 5 to 40°C ambient temperature and 20 to 70%, related humidity conditions.
- (2) The product is recommended to be used within one year after shipment. Check solderability in case of shelf life extension is needed.

#### Cautions:

- a. The corrosive gas reacts on the terminal electrodes of capacitors, and results in the poor solderability.
   Do not store the capacitors in the ambience of corrosive gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas etc.)
- b. In corrosive atmosphere, solderability might be degraded, and silver migration might occur to cause low reliability.
- c. Due to the dewing by rapid humidity change, or the photochemical change of the terminal electrode by direct sunlight, the solderability and electrical performance may deteriorate. Do not store capacitors under direct sunlight or dewing condition. To store products on the shelf and avoid exposure to moisture.

Approval Sheet

## **■** Recommended soldering conditions

The lead-free termination MLCCs are not only to be used on SMT against lead-free solder paste, but also suitable against lead-containing solder paste. If the optimized solder joint is requested, increasing soldering time, temperature and concentration of  $N_2$  within oven are recommended.

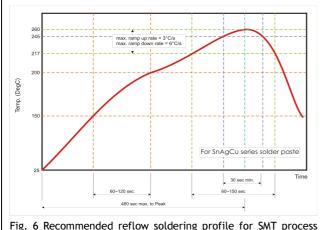


Fig. 6 Recommended reflow soldering profile for SMT process with  ${\sf SnAgCu}$  series solder paste.

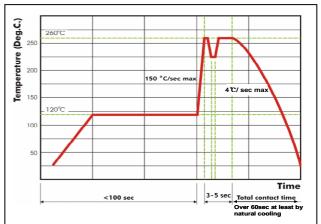


Fig. 7 Recommended wave soldering profile for SMT process with SnAgCu series solder.

